



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/879,231  
Filing Date ..... June 11, 2001  
Inventor ..... Garo J. Derderian, et al  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2818  
Examiner ..... T. Le  
Attorney's Docket No. .... MI22-1748  
Title: Capacitor Constructions Having a Conductive Layer

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

To: Commissioner for Patents  
PO Box 1450  
Art Unit 2818  
Alexandria, VA 22313-1450

From: James E. Lake (Tel. 509-624-4276; Fax 509-838-3424)  
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In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

Pursuant to 37 C.F.R. §1.98(a)(2)(1) no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether all the submitted references are prior art. Citation of these references is respectfully requested.

Respectfully submitted,

Date: 16 Mar 2005

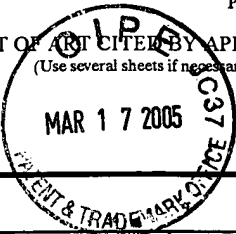
Attorney: [Signature]

James E. Lake  
Reg. No. 44,854

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1748		SERIAL NO. 09/879,231	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Garo J. Derderian			
				FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,482,740	11/02	Soininen et al			
	AB	5,908,947	06/99	Vaartstra			
	AC	6,403,156	06/02	Jang			
	AD	6,746,930	06/04	Yang			
	AE	2002/0142488	10/02	Hong, Suk-Kyoung			
	AF	2005/0018381	07/03	McClure			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP	Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level," Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.					
	AQ	T. Suntola, Atomic Layer Epitaxy, Handbook of Crystal Growth, Vol. 3, 1994, pp. 603-663.					
	AR	Leskela and Ritala, ALD Precursor Chemistry: Evolution and Future Challenges, J. Phys. IV France 9 (1999), pages 837-852.					
	AS	Ritala et al, "Perfectly Conformal TiN and Al <sub>2</sub> O <sub>3</sub> Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, pp. 7-9.					
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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				FILING DATE June 11, 2001		GROUP 2818	

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 PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	09/653,156	Agarwal (as amended 8/12/02, 2/18/03, 10/13/03, 3/30/04, 12/27/04)			08/2000	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AP		
	AQ		
	AR		
	AS		

EXAMINER	DATE CONSIDERED
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